

## 30V N-Channel Enhancement Mode MOSFET

### Description

The AP170N03D uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS}=30V$   $I_D=170A$

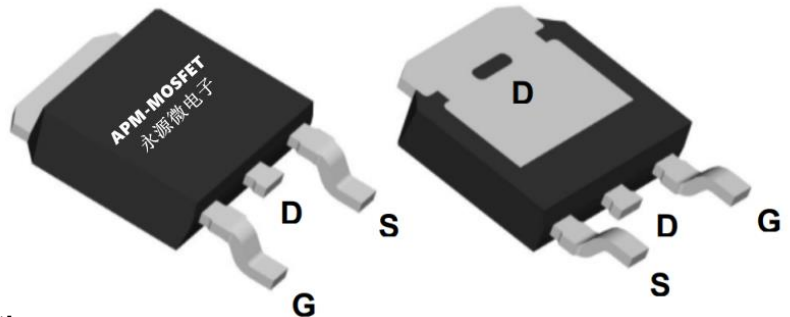
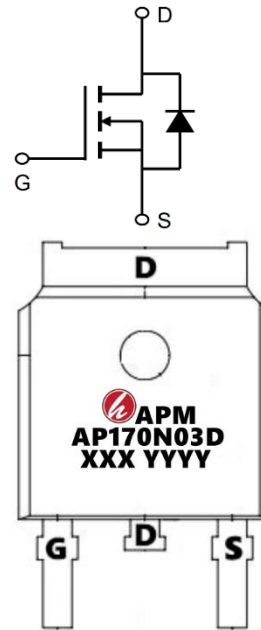
$R_{DS(ON)} < 2.5m\Omega$  @  $V_{GS}=10V$  (Type: 2.1m $\Omega$ )

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP170N03D	TO-252-3L	AP170N03D XXXX YYYY	2500

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>1</sup>	170	A
$I_D@T_C=75^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>1</sup>	96	A
IDM	Pulsed Drain Current <sup>2</sup>	480	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	289	mJ
IAS	Avalanche Current	34	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	57	W
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	12	W
TSTG $T_J$	Operating Junction /Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	25	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	2.2	$^\circ\text{C}/\text{W}$

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### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	30	-	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	-	-	1.0	μA
IGSS	Gate-Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.6	2.5	V
RDS(ON)	Static Drain-Source ON-Resistance <sup>(4)</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A	-	2.1	2.5	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A	-	2.9	3.8	mΩ
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz	-	5065	-	pF
C <sub>oss</sub>	Output Capacitance		-	574	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	472	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = 0 to 10V, V <sub>DS</sub> = 15V, I <sub>D</sub> = 30A	-	97	-	nC
Q <sub>gs</sub>	Gate Source Charge		-	20	-	nC
Q <sub>gd</sub>	Gate Drain("Miller") Charge		-	23	-	nC
td(on)	Turn-On DelayTime	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 15V I <sub>D</sub> = 30A, R <sub>GEN</sub> = 3Ω	-	16	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	30	-	ns
td(off)	Turn-Off DelayTime		-	54	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	19	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	120	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	480	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	I <sub>F</sub> = 30A, di/dt = 100A/us	-	23	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	14	-	nC

**Note :**

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
3. The EAS data shows Max. rating . The test condition is VDD=24V,VGS=10V,L=0.5mH,IAS=34A
4. The power dissipation is limited by 175°C junction temperature
5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

### Typical Characteristics

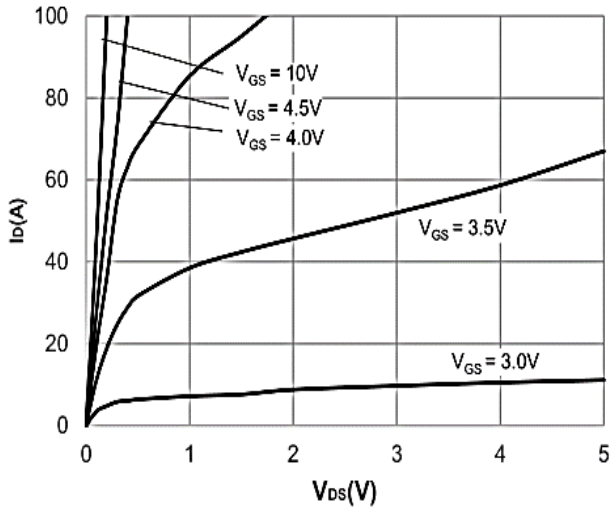


Figure 1: Output Characteristics

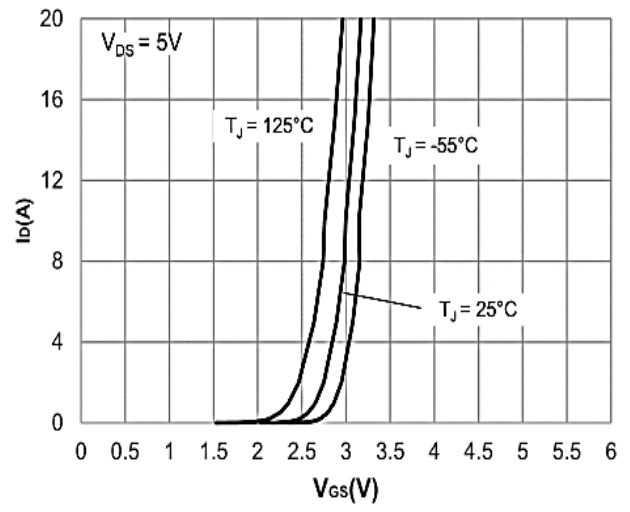


Figure 2: Typical Transfer Characteristics

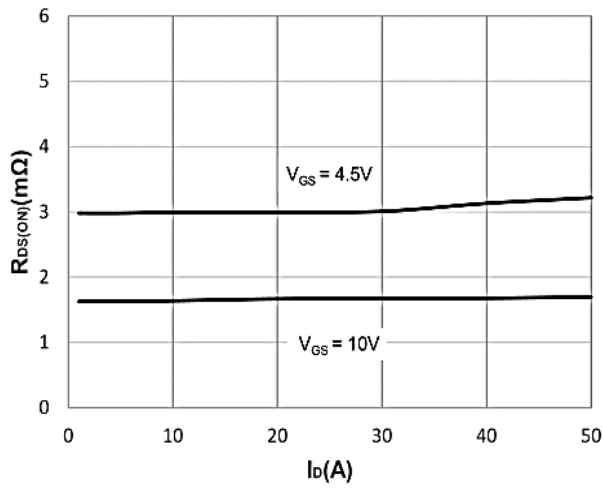


Figure 3: On-resistance vs. Drain Current

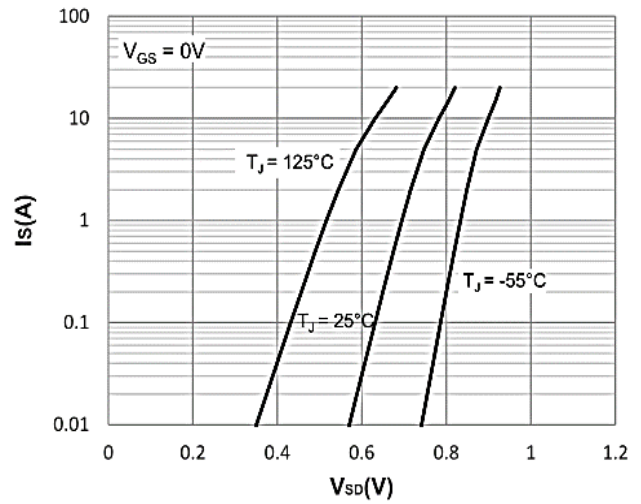


Figure 4: Body Diode Characteristics

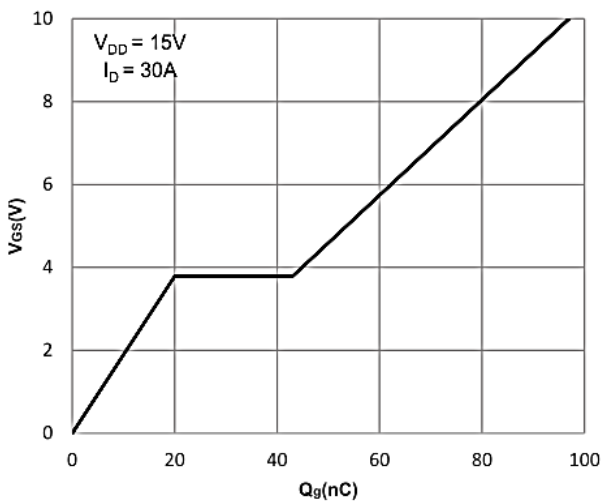


Figure 5: Gate Charge Characteristics

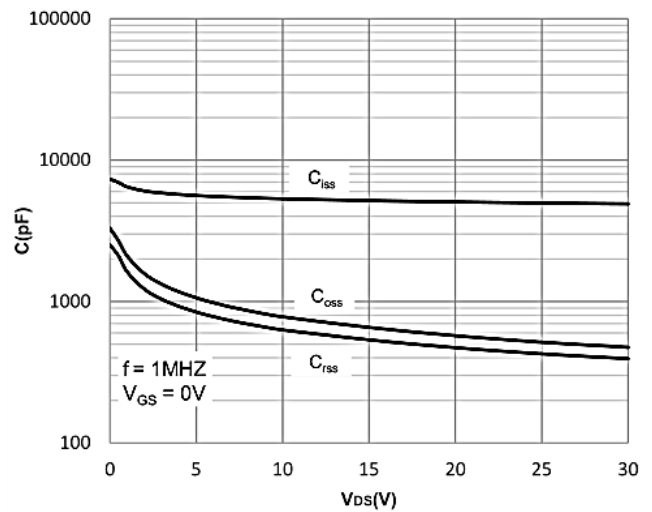
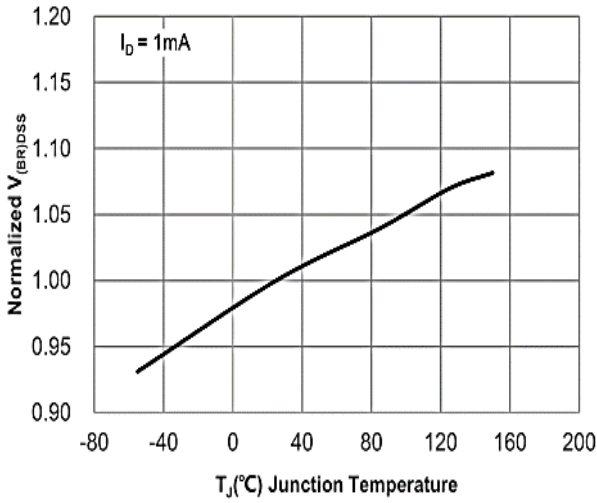


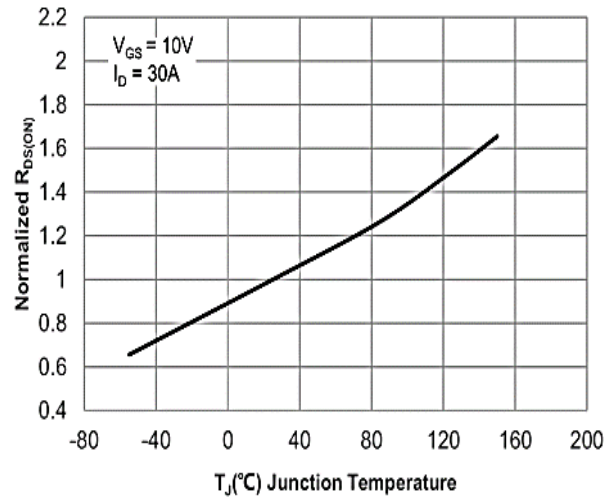
Figure 6: Capacitance Characteristics



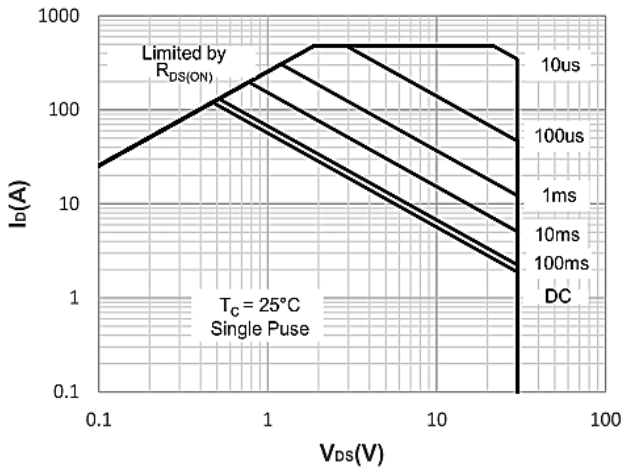
**30V N-Channel Enhancement Mode MOSFET**



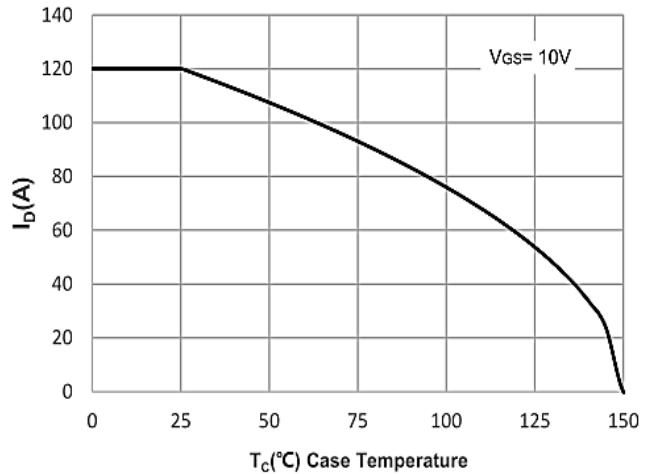
**Figure 7: Normalized Breakdown voltage vs. Junction Temperature**



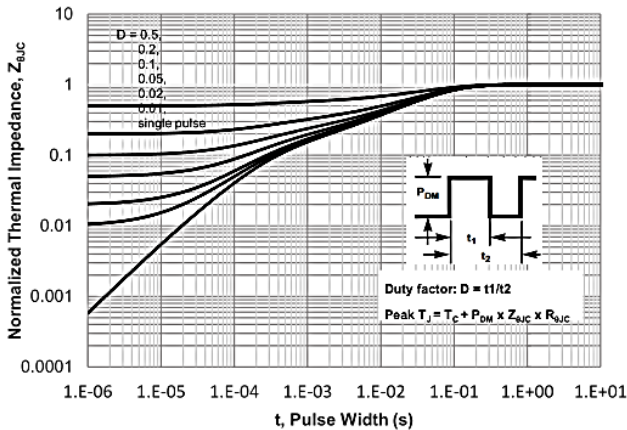
**Figure 8: Normalized on Resistance vs. Junction Temperature**



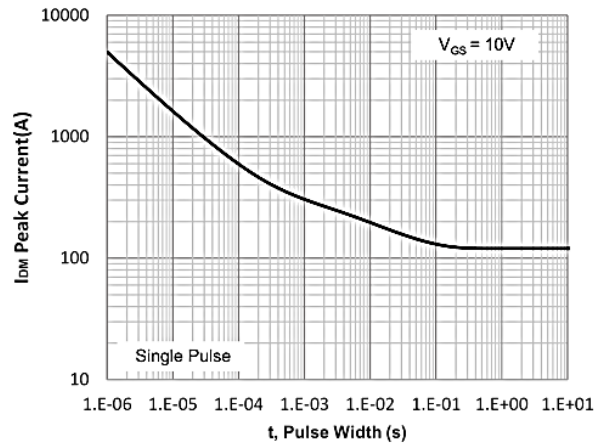
**Figure 9: Maximum Safe Operating Area**



**Figure 10: Maximum Continuous Driant Current vs. Case Temperature**

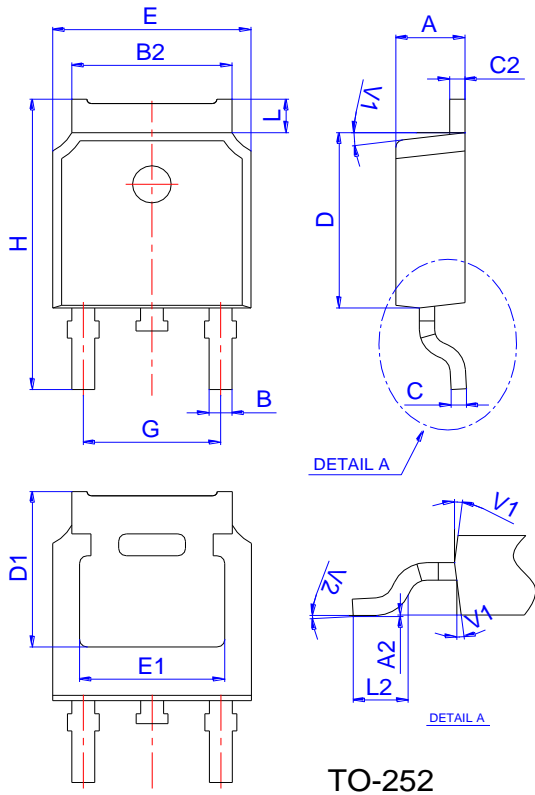


**Figure 11: Normalized Maximum Transient**



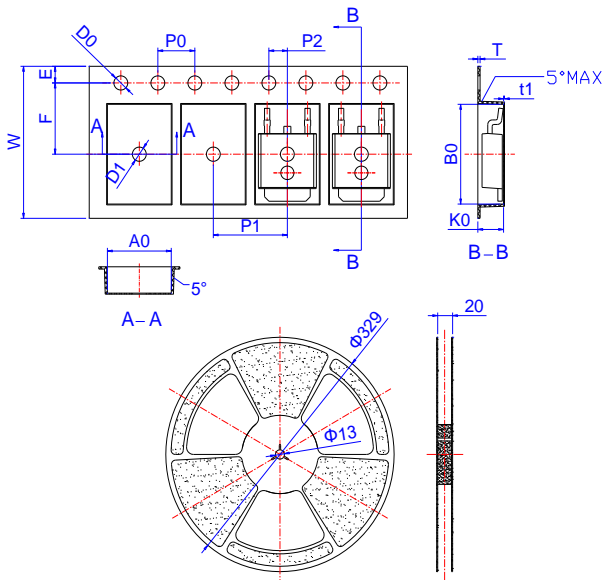
**Figure 12: Peak Current Capacity Thermal Impedance**

### Package Mechanical Data:TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

### Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
REV1.0	2023/6/21	Initial release

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